

Notice of References Cited

Application/Control No.

10/568,393

Applicant(s)/Patent Under

Reexamination

TOKUNAGA ET AL.

Examiner

RIP A. LEE

Art Unit

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-			
B	US-			
C	US-			
D	US-			
E	US-			
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J	US-			
K	US-			
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FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 2003-286369	10-2003	Japan	Watanabe et al.	C08L 21/00
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	JP 2003-286369 (10-2003) abstract and translation in English
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